

<b>Notice of References Cited</b>	Application/Control No. 10/666,790	Applicant(s)/Patent Under Reexamination TSUKAMOTO ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2004/0053116	03-2004	Skinlo, David M.	429/094
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